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(54) **METHOD FOR COLLECTING FAILURE INFORMATION FOR A MEMORY USING AN EMBEDDED TEST CONTROLLER**

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714/736, 704

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(57) **ABSTRACT**

A method of collecting failure information when testing a memory comprises performing a test of the memory according to a test algorithm, and, while performing the test, counting failure events which occur after a predetermined number of masked events; stopping the test upon occurrence of a stopping criterion which comprises one of occurrence of a first failure event, a change of a test operation; a change of a memory column address; a change of a memory row address; a change of a memory bank address; and a change of a test algorithm phase; and storing failure information.

**52 Claims, 3 Drawing Sheets**

